



CONNECTED PV 4.0

Industry Leading Process Analytics for SMART PV Manufacturing

Tom Thieme | Intersolar & VDMA Workshop | October 6th 2021

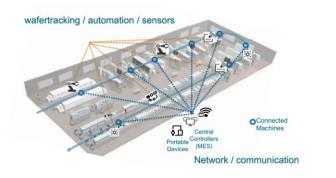
CONNECTED PV 4.0 | Introduction





2018 VDMA for Smart PV Fab's

- ➡ Latest Technology
 - Fully automated, self-learning,
 - High yield & productivity
- Flexible Concept
 - Most complete quality inspection capabilities
 - Fast ramp-up, design change and operation friendly

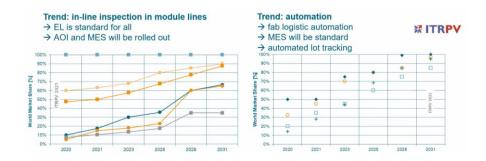


2021 ITRPV Roadmap

➡ Smart PV fab trends

₩ ITRPV

- More inline inspection system have to be integrated
- Targeting cost reduction & yield improvement
- Automated recipe management and data analytics

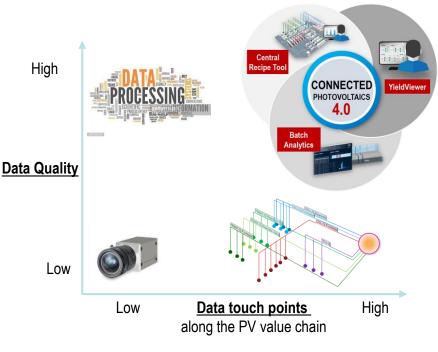


CONNECTED PV 4.0 | Introduction

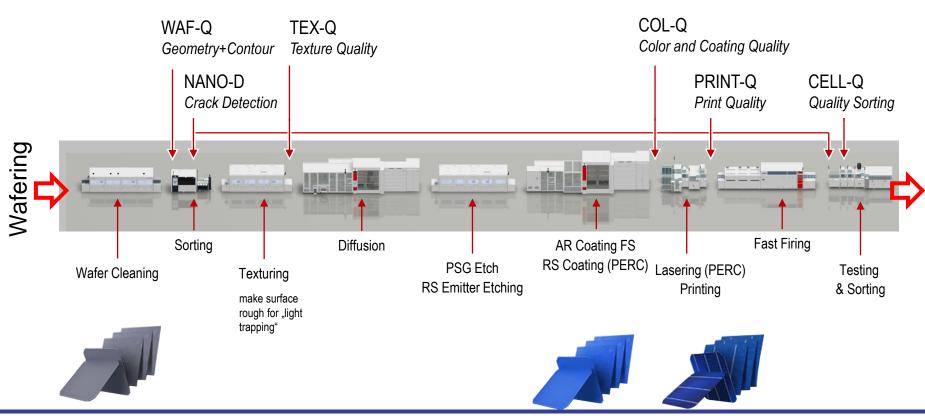
Market driver

- Smart PV fab trends
 - More inline inspection system have to be integrated
 - Targeting cost reduction & yield improvement
 - Automated recipe management and data analytics
- Latest Technology
 - Fully automated, self-learning,
 - High yield & productivity
- ➡ Flexible Concept
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Quality of Process Data





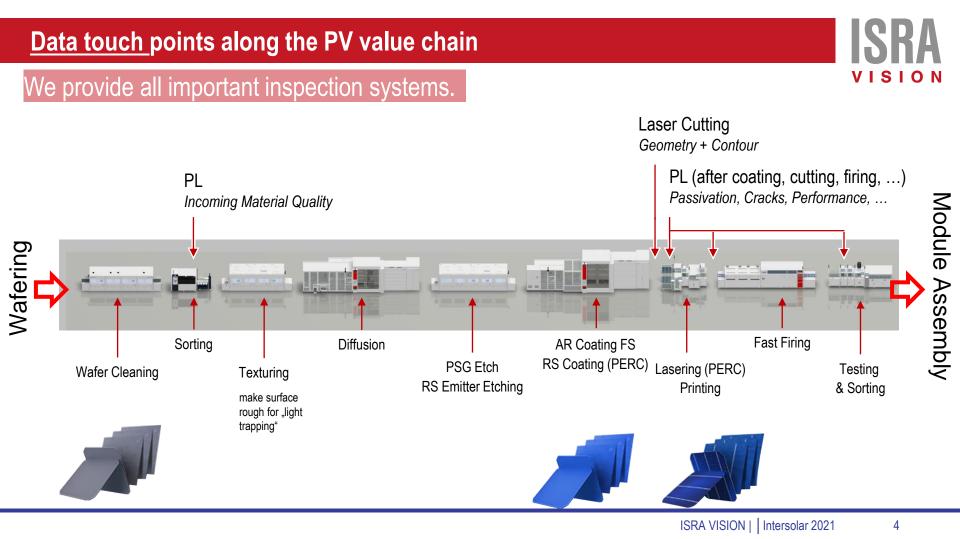


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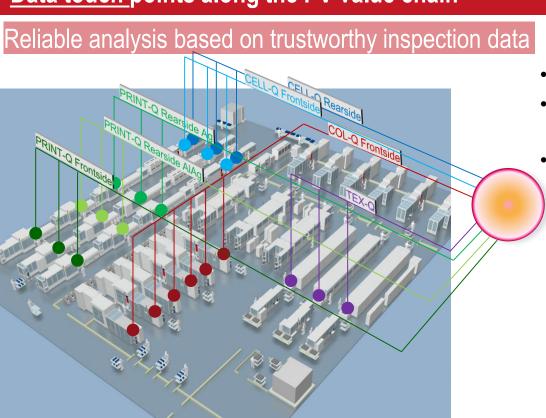
Module

Assembly



Data touch points along the PV value chain





- Connect all systems
- Manage all systems
 - Central Recipe Management
- Central data analytics
 - CPV YieldViewer
 - CPV BoatViewer
 - CPV Defect Heatmap
 - Trend charts

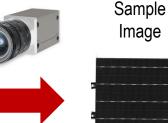


Data Quality | From Acquisition to Data Processing

Image

To obtain identical data...





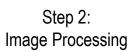


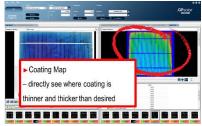




Image Data

Sep 3:

Data Processing/Classification



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To obtain identical image data, system setup is key to success

Step 1:

Image Acquisition

Flatfield calibration Flash calibration Metrological calibration Smart colour calibration

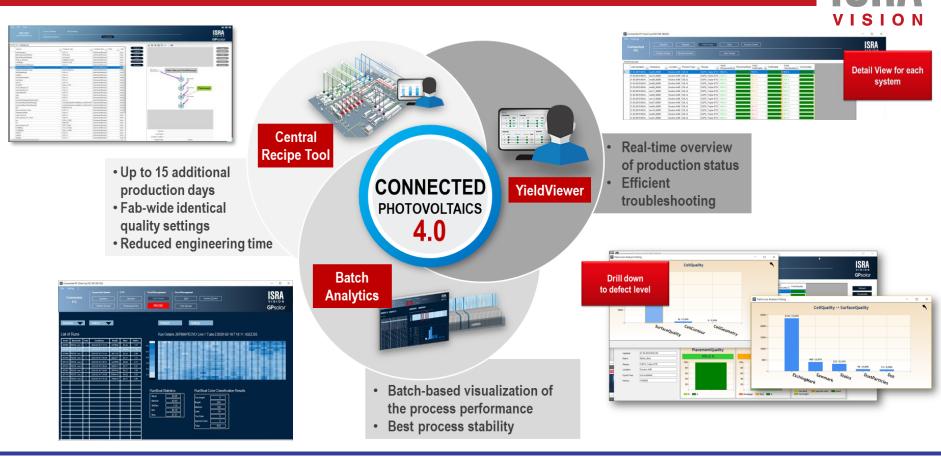
All systems must use same image processing settings on identically generated images

Processing Example: 1 px with 0...50 GV \rightarrow interrupt 1 px with 50...80 GV \rightarrow thinning All systems must apply same classification settings (recipe) to the same data

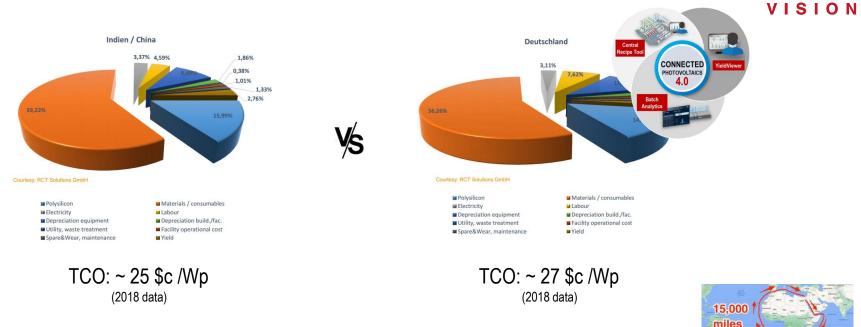
Classification Example: Total Interrupt Length < 5 mm

► Live Image Bad Image History Print Finger Map Cumulative Defect **Overlay** Coating Map

CONNECTED PV 4.0 | Merge Advanced Image Data Along the Value Chain



CONNECTED PV 4.0 | Economical considerations



- 2020/2021 => global supply chain issues increases logistic cost significantly
- 2020/2021 => cost efficient & smart GW manufacturing pay's off anywhere globally
- Smart & intelligent process cost saving & yield improving fab solutions are "Must have" in PV

CONNECTED PV 4.0 | A Solution to make PV in Europe attractive again!

Customer values

- **Real time** quality tracking
- **Full** production transparency
- Consistent quality standards
- Historical and trend analytics
- Comparable process insights
- Identify champion lines
- Industry **proven** data system
- Fast recipe changes & adoption
- Reliable decision base



Central yield analysis with Central Recipe Tool

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Thank you for your attention

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